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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	1232
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	140
Number of Gates	8000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	172-CQFP with Tie Bar
Supplier Device Package	172-CQFP (63.37x63.37)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microsemi/5962-9215602myc">https://www.e-xfl.com/product-detail/microsemi/5962-9215602myc</a>

## Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-5 for commercial, worst case conditions.

**Table 2-5 • Standby Power Calculation**

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

## Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

## Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 3.

$$\text{Power } (\mu\text{W}) = C_{\text{EQ}} * V_{\text{CC}}^2 * F$$

EQ 3

Where:

$C_{\text{EQ}}$  is the equivalent capacitance expressed in pF.

VCC is the power supply in volts.

F is the switching frequency in MHz.

Equivalent capacitance is calculated by measuring ICC active at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency independent so that the results may be used over a wide range of operating conditions. Equivalent capacitance values are shown in Table 2-6.

**Table 2-6 • CEQ Values for Microsemi FPGAs**

Item	CEQ Value
Modules ( $C_{\text{EQM}}$ )	5.8
Input Buffers ( $C_{\text{EQI}}$ )	12.9
Output Buffers ( $C_{\text{EQO}}$ )	23.8
Routed Array Clock Buffer Loads ( $C_{\text{EQCR}}$ )	3.9

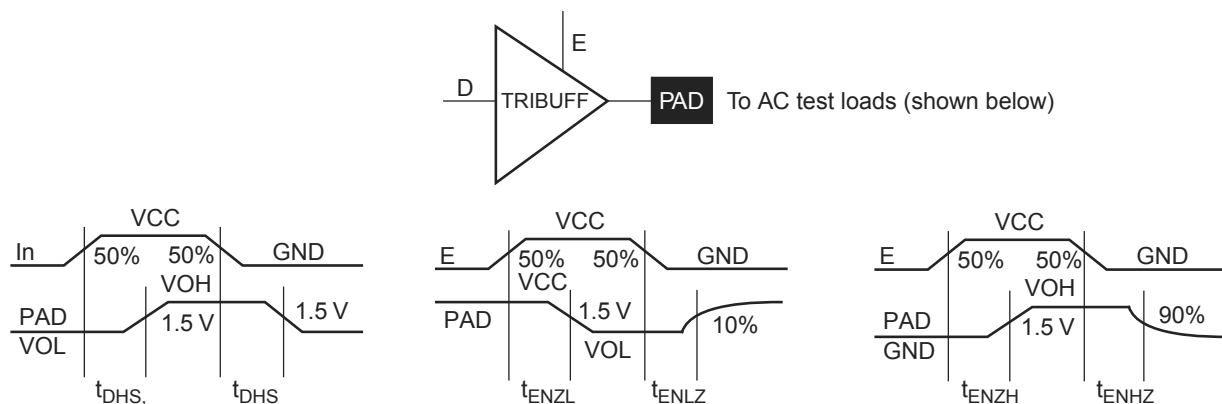
## Determining Average Switching Frequency

To determine the switching frequency for a design, you must have a detailed understanding of the data input values to the circuit. The following guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are given in Table 2-8.

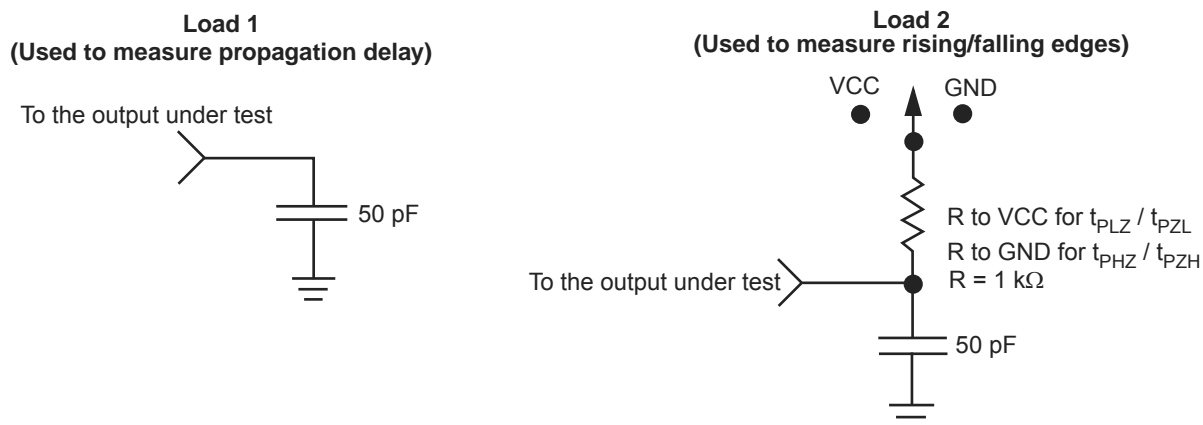
**Table 2-8 • Guidelines for Predicting Power Dissipation**

Data	Value
Logic Modules (m)	80% of modules
Inputs switching (n)	# inputs/4
Outputs switching (p)	# output/4
First routed array clock loads (q1)	40% of sequential modules
Second routed array clock loads (q2)	40% of sequential modules
Load capacitance ( $C_L$ )	35 pF
Average logic module switching rate ( $f_m$ )	F/10
Average input switching rate ( $f_n$ )	F/5
Average output switching rate ( $f_p$ )	F/10
Average first routed array clock rate ( $f_{q1}$ )	F
Average second routed array clock rate ( $f_{q2}$ )	F/2

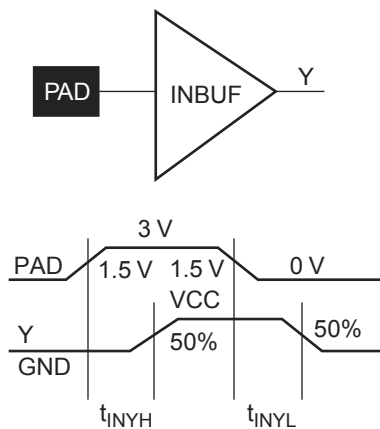
## Parameter Measurement



**Figure 2-2 • Output Buffer Delays**



**Figure 2-3 • AC Test Loads**



**Figure 2-4 • Input Buffer Delays**

## Timing Derating Factor (Temperature and Voltage)

**Table 2-9 • Timing Derating Factor (Temperature and Voltage)**

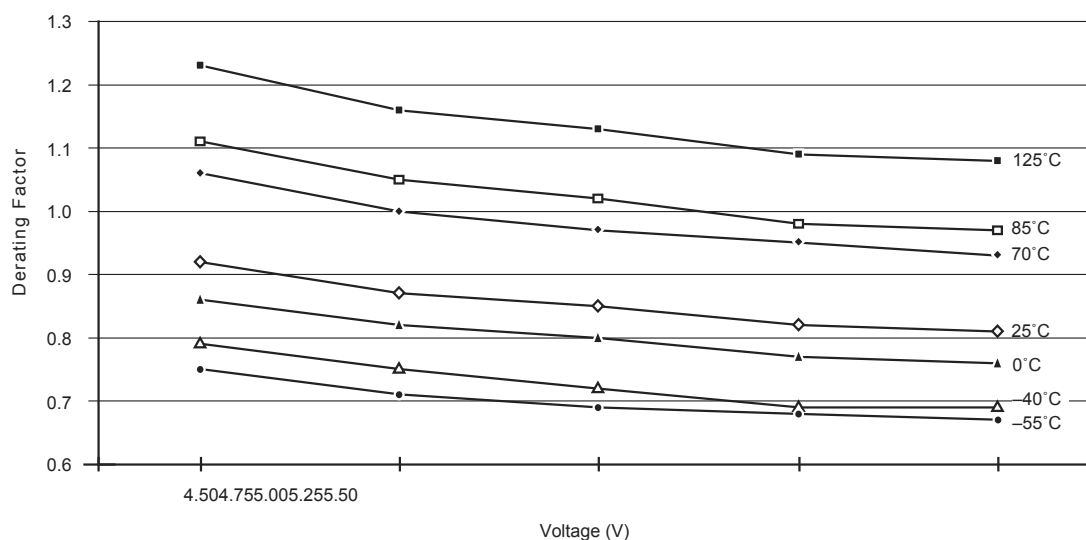
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.69	1.11	0.67	1.23

**Table 2-10 • Timing Derating Factor for Designs at Typical Temperature ( $T_J = 25^\circ\text{C}$ ) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85
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**Table 2-11 • Temperature and Voltage Derating Factors  
(normalized to Worst-Case Commercial,  $T_J = 4.75\text{ V}$ ,  $70^\circ\text{C}$ )**

	-55	-40	0	25	70	85	125
<b>4.50</b>	0.75	0.79	0.86	0.92	1.06	1.11	1.23
<b>4.75</b>	0.71	0.75	0.82	0.87	1.00	1.05	1.13
<b>5.00</b>	0.69	0.72	0.80	0.85	0.97	1.02	1.13
<b>5.25</b>	0.68	0.69	0.77	0.82	0.95	0.98	1.09
<b>5.50</b>	0.67	0.69	0.76	0.81	0.93	0.97	1.08



*Note: This derating factor applies to all routing and propagation delays.*

**Figure 2-9 • Junction Temperature and Voltage Derating Curves  
(normalized to Worst-Case Commercial,  $T_J = 4.75\text{ V}$ ,  $70^\circ\text{C}$ )**

## A1225A Timing Characteristics

**Table 2-12 • A1225A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Logic Module Propagation Delays <sup>1</sup>		–2 Speed <sup>3</sup>		–1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>PD1</sub>	Single Module		3.8		4.3		5.0	ns
t <sub>CO</sub>	Sequential Clock to Q		3.8		4.3		5.0	ns
t <sub>GO</sub>	Latch G to Q		3.8		4.3		5.0	ns
t <sub>RS</sub>	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
<b>Predicted Routing Delays<sup>2</sup></b>								
t <sub>RD1</sub>	FO = 1 Routing Delay		1.1		1.2		1.4	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.7		1.9		2.2	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		2.3		2.6		3.0	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		2.8		3.1		3.7	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		4.4		4.9		5.8	ns
<b>Sequential Timing Characteristics<sup>3,4</sup></b>								
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t <sub>HD</sub>	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.5		5.0		6.0		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Clock Asynchronous Pulse Width	4.5		5.0		6.0		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	9.4		11.0		13.0		ns
t <sub>INH</sub>	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t <sub>OUTH</sub>	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>OUTSU</sub>	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency		105.0		90.0		75.0	MHz

**Notes:**

1. For dual-module macros, use t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, t<sub>CO</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, or t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>SUD</sub>—whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.
4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

## A1240A Timing Characteristics

**Table 2-15 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Logic Module Propagation Delays <sup>1</sup>		–2 Speed <sup>3</sup>		–1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>PD1</sub>	Single Module		3.8		4.3		5.0	ns
t <sub>CO</sub>	Sequential Clock to Q		3.8		4.3		5.0	ns
t <sub>GO</sub>	Latch G to Q		3.8		4.3		5.0	ns
t <sub>RS</sub>	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
<b>Predicted Routing Delays<sup>2</sup></b>								
t <sub>RD1</sub>	FO = 1 Routing Delay		1.4		1.5		1.8	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.7		2.0		2.3	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		2.3		2.6		3.0	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		3.1		3.5		4.1	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		4.7		5.4		6.3	ns
<b>Sequential Timing Characteristics<sup>3,4</sup></b>								
t <sub>SUD</sub>	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t <sub>HD</sub>	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t <sub>SUENA</sub>	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t <sub>HENA</sub>	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t <sub>WCLKA</sub>	Flip-Flop (Latch) Clock Active Pulse Width	4.5		6.0		6.5		ns
t <sub>WASYN</sub>	Flip-Flop (Latch) Clock Asynchronous Pulse Width	4.5		6.0		6.5		ns
t <sub>A</sub>	Flip-Flop Clock Input Period	9.8		12.0		15.0		ns
t <sub>INH</sub>	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t <sub>OUTH</sub>	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t <sub>OUTSU</sub>	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f <sub>MAX</sub>	Flip-Flop (Latch) Clock Frequency		100.0		80.0		66.0	MHz

**Notes:**

1. For dual-module macros, use t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, t<sub>CO</sub> + t<sub>RD1</sub> + t<sub>PDn</sub>, or t<sub>PD1</sub> + t<sub>RD1</sub> + t<sub>SUD</sub>—whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.
4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

**Table 2-20 • A1280A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

TTL Output Module Timing <sup>1</sup>		–2 Speed		–1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>DLH</sub>	Data to Pad High		8.1		9.0		10.6	ns
t <sub>DHL</sub>	Data to Pad Low		10.2		11.4		13.4	ns
t <sub>ENZH</sub>	Enable Pad Z to High		9.0		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.8		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.3		12.7		14.9	ns
d <sub>TLH</sub>	Delta Low to High		0.07		0.08		0.09	ns/pF
d <sub>THL</sub>	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing <sup>1</sup>								
t <sub>DLH</sub>	Data to Pad High		10.3		11.5		13.5	ns
t <sub>DHL</sub>	Data to Pad Low		8.5		9.6		11.2	ns
t <sub>ENZH</sub>	Enable Pad Z to High		9.0		10.0		11.8	ns
t <sub>ENZL</sub>	Enable Pad Z to Low		11.8		13.2		15.5	ns
t <sub>ENHZ</sub>	Enable Pad High to Z		7.1		8.0		9.4	ns
t <sub>ENLZ</sub>	Enable Pad Low to Z		8.4		9.5		11.1	ns
t <sub>GLH</sub>	G to Pad High		9.0		10.2		11.9	ns
t <sub>GHL</sub>	G to Pad Low		11.3		12.7		14.9	ns
d <sub>TLH</sub>	Delta Low to High		0.12		0.13		0.16	ns/pF
d <sub>THL</sub>	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. Delays based on 50 pF loading.
2. SSO information can be found at [www.microsemi.com/soc/techdocs/appnotes/board\\_consideration.aspx](http://www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx).



## Pin Descriptions

### **CLKA**                      **Clock A (Input)**

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **CLKB**                      **Clock B (Input)**

TTL Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **DCLK**                      **Diagnostic Clock (Input)**

TTL Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

### **GND**                      **Ground**

Low supply voltage.

### **I/O**                      **Input/Output (Input, Output)**

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are automatically driven Low by the ALS software.

### **MODE**                      **Mode (Input)**

The MODE pin controls the use of multifunction pins (DCLK, PRA, PRB, SDI). When the MODE pin is High, the special functions are active. When the MODE pin is Low, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled High when required.

### **NC**                      **No Connection**

This pin is not connected to circuitry within the device.

### **PRA**                      **Probe A (Output)**

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

### **PRB**                      **Probe B (Output)**

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

### **SDI**                      **Serial Data Input (Input)**

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

### **SDO**                      **Serial Data Output (Output)**

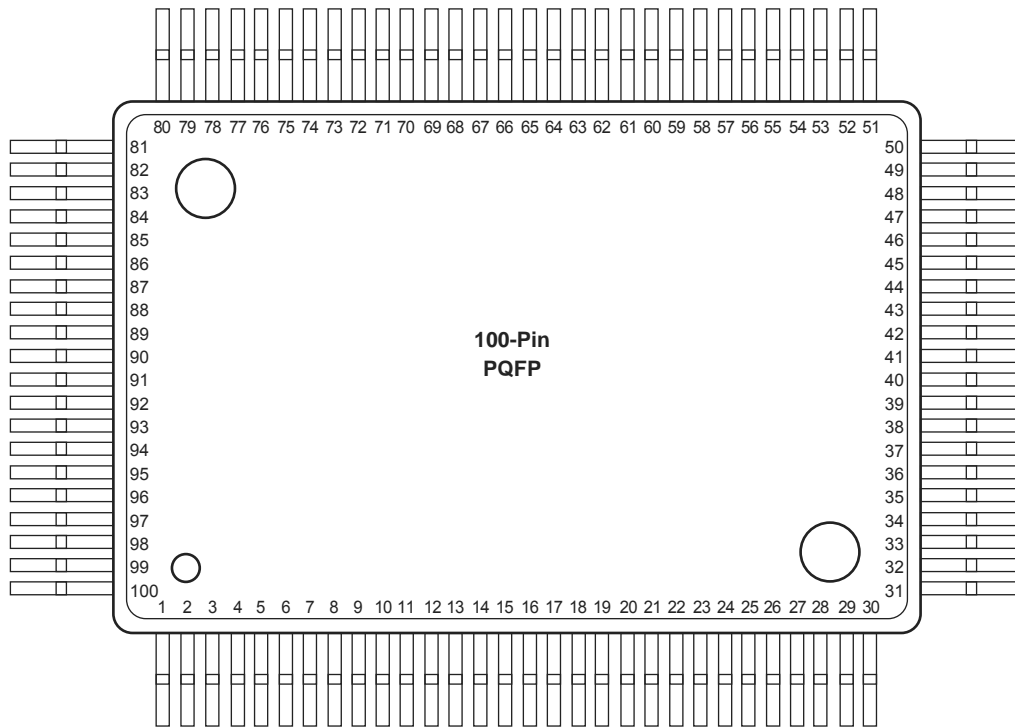
Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

### **VCC**                      **5.0 V Supply Voltage**

High supply voltage.



## PQ100

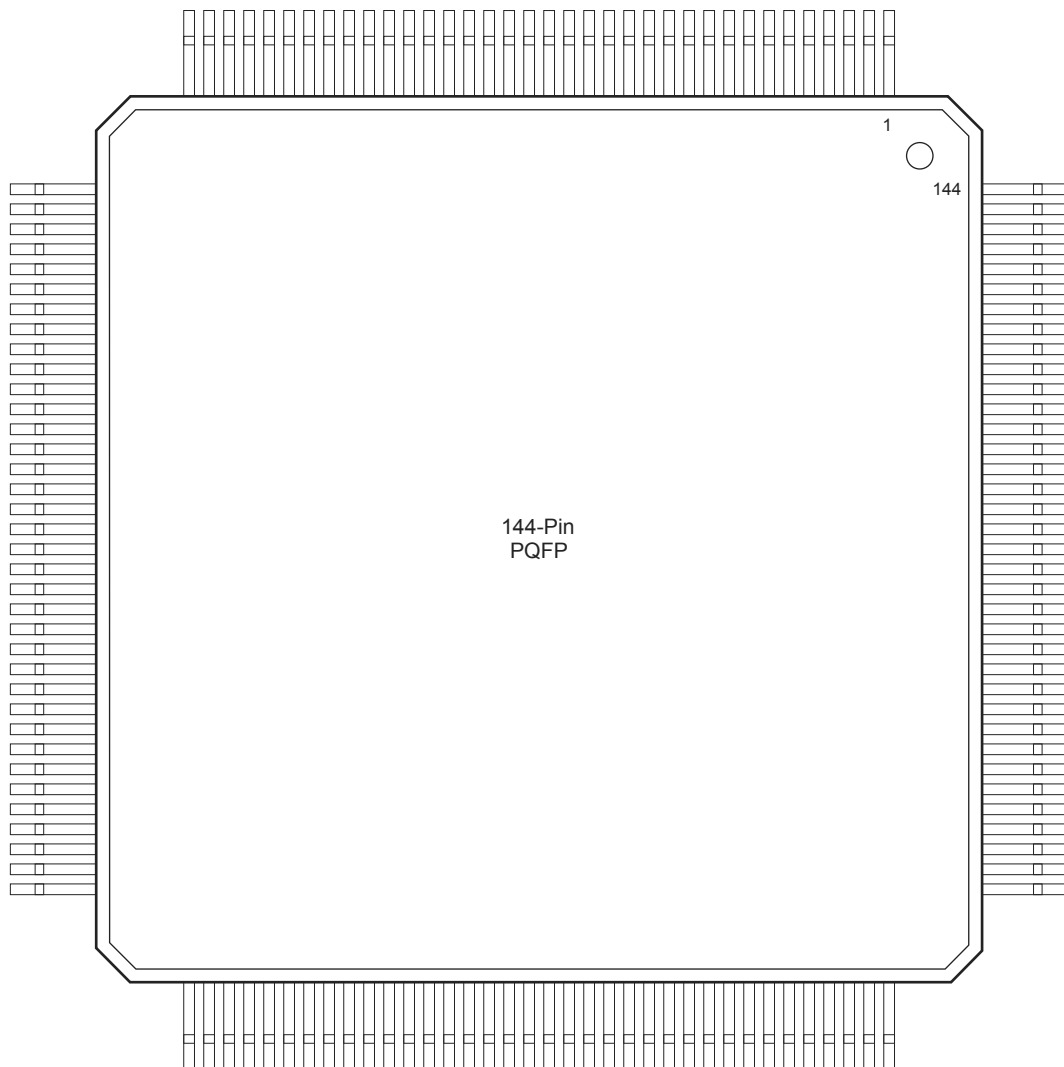


### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

## PQ144

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### **Note**

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

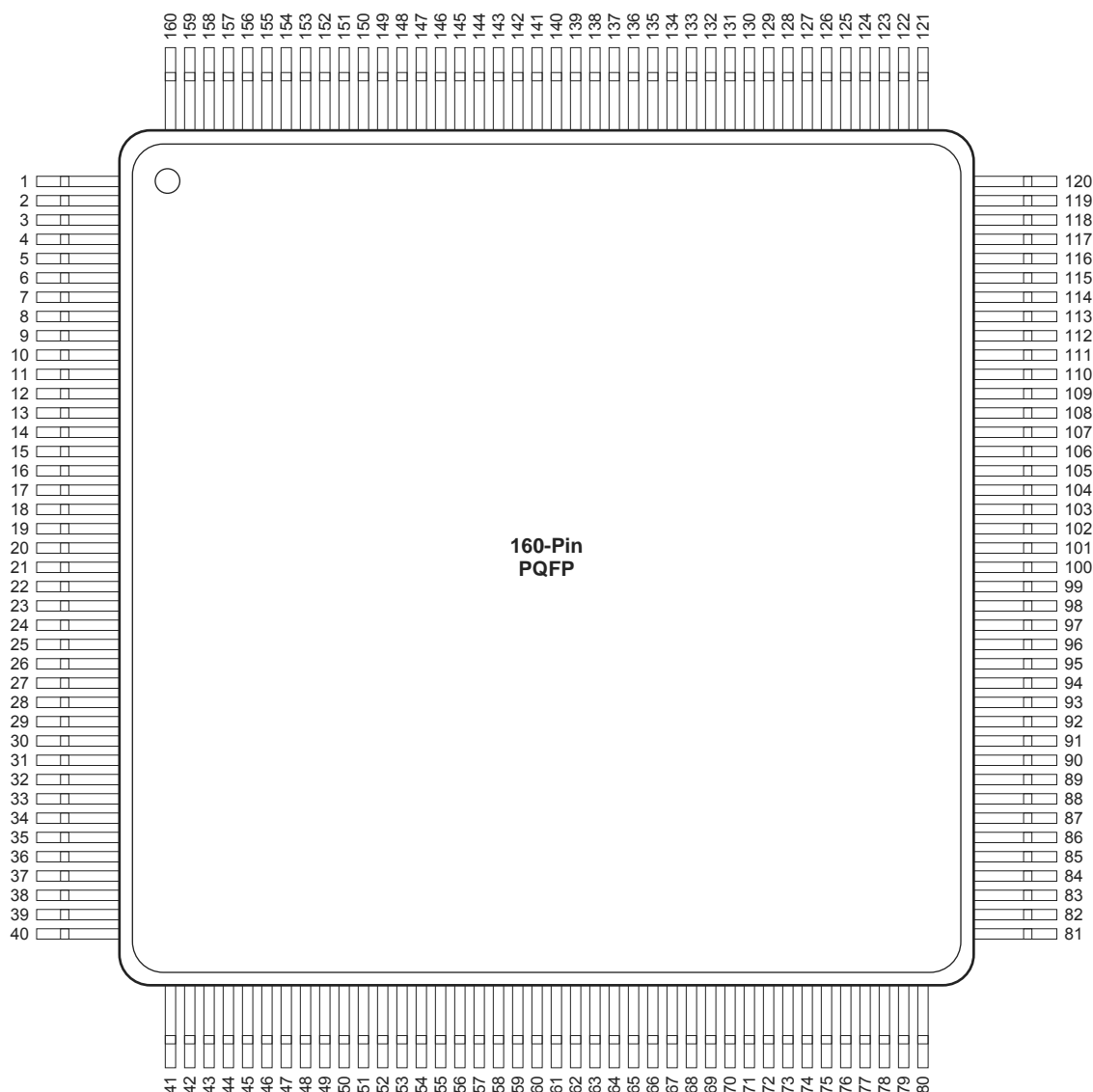
PQ144	
Pin Number	A1240A Function
2	MODE
9	GND
10	GND
11	GND
18	VCC
19	VCC
20	VCC
21	VCC
28	GND
29	GND
30	GND
44	GND
45	GND
46	GND
54	VCC
55	VCC
56	VCC
64	GND
65	GND
71	SDO
79	GND
80	GND
81	GND
88	GND

PQ144	
Pin Number	A1240A Function
89	VCC
90	VCC
91	VCC
92	VCC
93	VCC
100	GND
101	GND
102	GND
110	SDI, I/O
116	GND
117	GND
118	GND
123	PRA, I/O
125	CLKA, I/O
126	VCC
127	VCC
128	VCC
130	CLKB, I/O
132	PRB, I/O
136	GND
137	GND
138	GND
144	DCLK, I/O

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

## PQ160



*Note:* This is the top view of the package

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

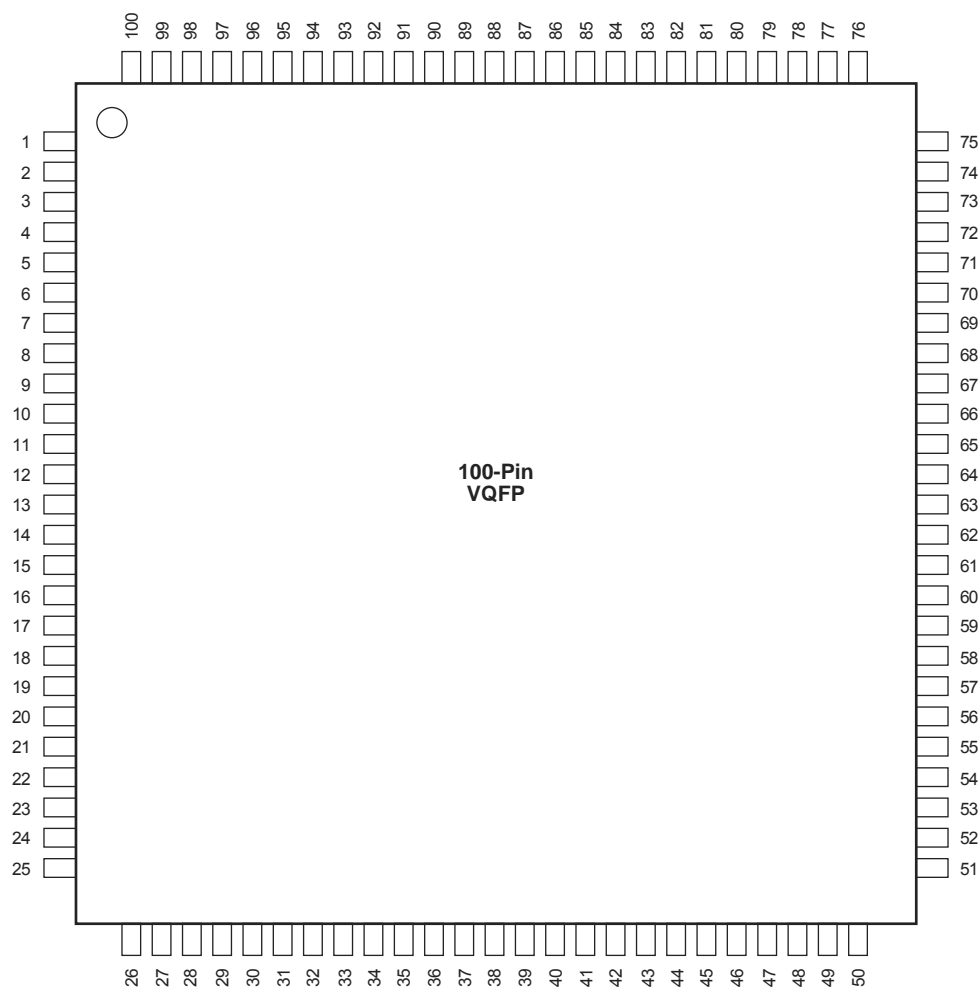
PQ160	
Pin Number	A1280A Function
2	DCLK, I/O
6	VCC
11	GND
16	PRB, I/O
18	CLKB, I/O
20	VCC
21	CLKA, I/O
23	PRA, I/O
30	GND
35	VCC
38	SDI, I/O
40	GND
44	GND
49	GND
54	VCC
57	VCC
58	VCC
59	GND
60	VCC
61	GND
64	GND

PQ160	
Pin Number	A1280A Function
69	GND
80	GND
82	SDO
86	VCC
89	GN
98	GND
99	GND
109	GND
114	VCC
120	GND
125	GND
130	GND
135	VCC
138	VCC
139	VCC
140	GND
145	GND
150	VCC
155	GND
159	MODE
160	GND

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

## VQ100

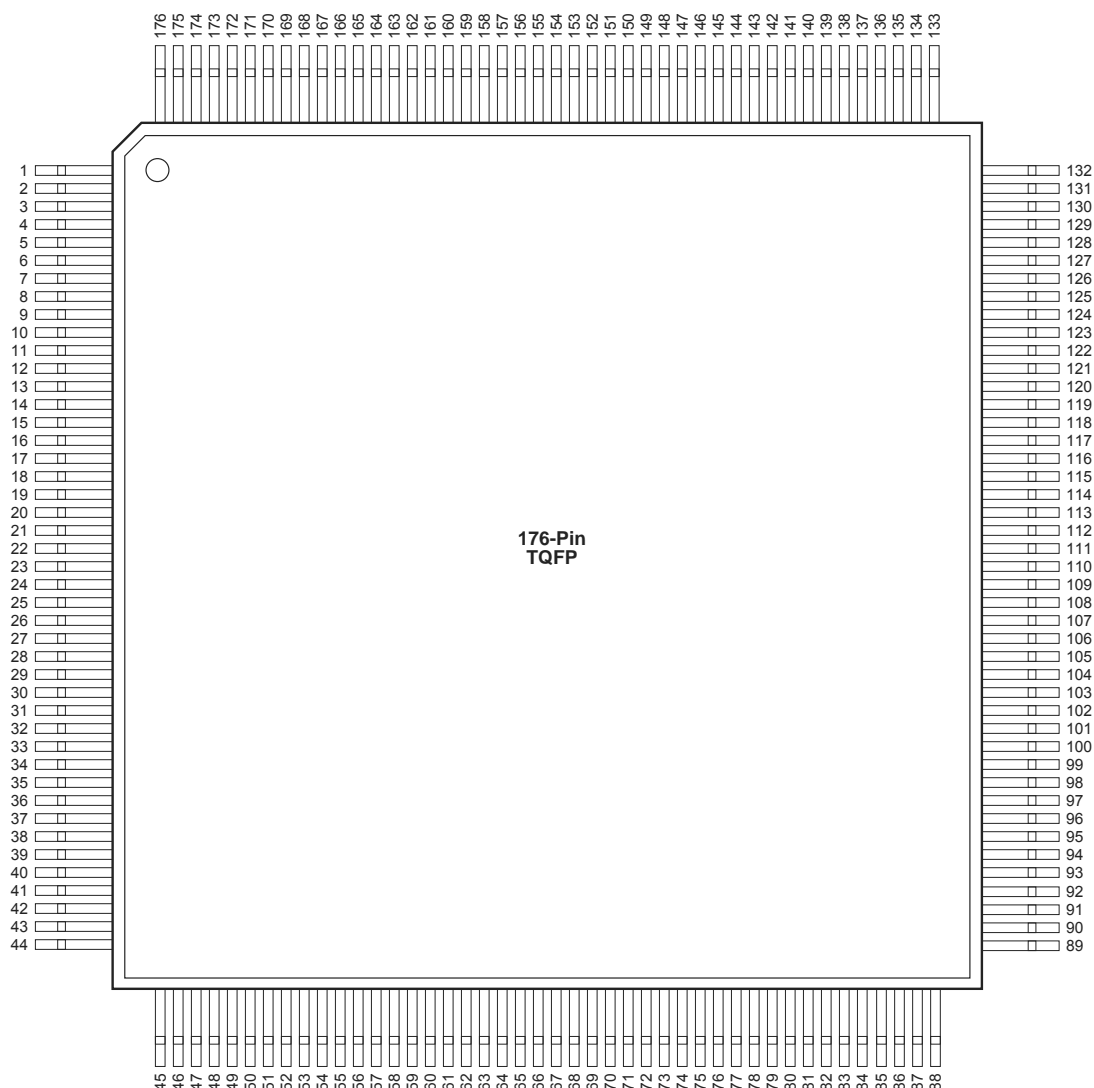


### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>



# TQ176



## Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

TQ176		
Pin Number	A1240A Function	A1280A Function
1	GND	GND
2	MODE	MODE
8	NC	NC
10	NC	I/O
11	NC	I/O
13	NC	VCC
18	GND	GND
19	NC	I/O
20	NC	I/O
22	NC	I/O
23	GND	GND
24	NC	VCC
25	VCC	VCC
26	NC	I/O
27	NC	I/O
28	VCC	VCC
29	NC	I/O
33	NC	NC
37	NC	I/O
38	NC	NC
45	GND	GND
52	NC	VCC
54	NC	I/O
55	NC	I/O
57	NC	NC
61	NC	I/O
64	NC	I/O
66	NC	I/O
67	GND	GND
68	VCC	VCC
74	NC	I/O
77	NC	NC
78	NC	I/O
80	NC	I/O

TQ176		
Pin Number	A1240A Function	A1280A Function
82	NC	VCC
86	NC	I/O
87	SDO	SDO
89	GND	GND
96	NC	I/O
97	NC	I/O
101	NC	NC
103	NC	I/O
106	GND	GND
107	NC	I/O
108	NC	I/O
109	GND	GND
110	VCC	VCC
111	GND	GND
112	VCC	VCC
113	VCC	VCC
114	NC	I/O
115	NC	I/O
116	NC	VCC
121	NC	NC
124	NC	I/O
125	NC	I/O
126	NC	NC
133	GND	GND
135	SDI, I/O	SDI, I/O
136	NC	I/O
140	NC	VCC
143	NC	I/O
144	NC	I/O
145	NC	NC
147	NC	I/O
151	NC	I/O
152	PRA, I/O	PRA, I/O
154	CLKA, I/O	CLKA, I/O

TQ176		
Pin Number	A1240A Function	A1280A Function
155	VCC	VCC
156	GND	GND
158	CLKB, I/O	CLKB, I/O
160	PRB, I/O	PRB, I/O
161	NC	I/O
165	NC	NC
166	NC	I/O
168	NC	I/O
170	NC	VCC
173	NC	I/O
175	DCLK, I/O	DCLK, I/O

*Notes:*

1. NC denotes no connection.
2. All unlisted pin numbers are user I/Os.
3. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG132	
Pin Number	A1240A Function
A1	MODE
B5	GND
B6	CLKB, I/O
B7	CLKA, I/O
B8	PRA, I/O
B9	GND
B12	SDI, I/O
C3	DCLK, I/O
C5	GND
C6	PRB, I/O
C7	VCC
C9	GND
D7	VCC
E3	GND
E11	GND
E12	GND
F4	GND
G2	VCC

PG132	
Pin Number	A1240A Function
G3	VCC
G4	VCC
G10	VCC
G11	VCC
G12	VCC
G13	VCC
H13	GND
J2	GND
J3	GND
J11	GND
K7	VCC
K12	GND
L5	GND
L7	VCC
L9	GND
M9	GND
N12	SDO

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

